

Figure 1 Pin Configuration (top view)

Pin Definitions and Functions

Pin	Symbol	Function
1	V_{S}	Supply Voltage
2	Q	Open Drain Input
3	Gnd	Ground



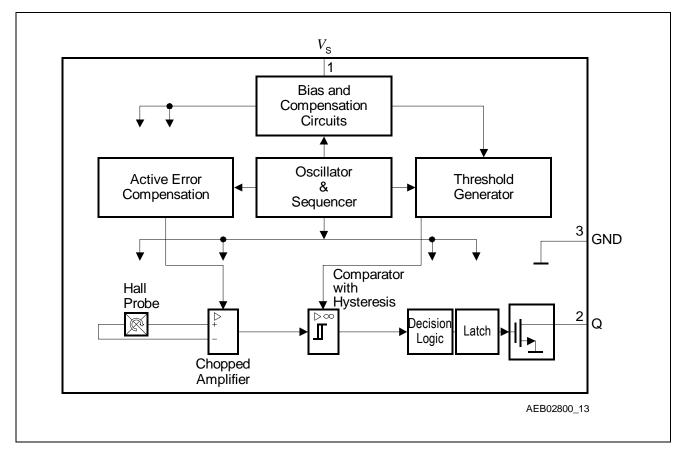


Figure 2 Block Diagram

Circuit Description

The Low Power Hall IC Switch comprises a Hall probe, bias generator, compensation circuits, oscillator, output latch and an n-channel open drain output transistor.

The bias generator provides currents for the Hall probe and the active circuits. Compensation circuits stabilize the temperature behavior and reduce technology variations.

The Active Error Compensation rejects offsets in signal stages and the influence of mechanical stress to the Hall probe caused by molding and soldering processes and other thermal stresses in the package. This chopper technique together with the threshold generator and the comparator ensures high accurate magnetic switching points.

Very low power consumption is achieved with a timing scheme controlled by an oscillator and a sequencer. This circuitry activates the sensor for $50~\mu s$ (typical operating time) sets the output state after sequential questioning of the switch points and latches it with the beginning of the following standby phase (max. 200~m s). In the standby phase the average current is reduced to typical $4~\mu A$. Because of the long standby time compared to the operating time the overall averaged current is only slightly higher than the standby current.

The output transistor can sink up to 1 mA with a maximal saturation voltage V_{QSAT} .



Absolute Maximum Ratings

Parameter	Symbol	Limi	t Values	Unit	Notes
		min.	max.		
Supply Voltage	V_{S}	- 0.3	5.5	V	
Supply Current	$I_{\mathbb{S}}$	- 1	2.5	mA	
Output Voltage	V_{Q}	- 0.3	5.5	V	
Output Current	I_{Q}	– 1	2	mA	
Junction temperature	T_{i}	- 40	150	°C	
Storage temperature	$T_{\mathbb{S}}$	- 40	150	°C	
Magnetic Flux Density	В	_	unlimited	mT	
Thermal Resistance P-SC59-3-x	R_{thJA}	_	35	K/W	

Note: Stresses above those listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ESD Protection

Human Body Model (HBM) tests according to: EOS/ESD Association Standard S5.1-1993 and Mil. Std. 883D method 3015.7

Parameter	Symbol	Limi	t Values	Unit	Notes	
		Min.	Max.			
ESD Voltage	V_{ESD}		± 4	kV	$R = 1.5 \text{ k}\Omega,$	
					C = 100 pF;	
					T = 25 °C	



Operating Range

Parameter	Symbol	Limit Values			Unit	Notes
		Min.	typ.	max.		
Supply voltage	V_{S}	2.4	2.7	5.5	V	1)
Output voltage	V_{Q}	- 0.3	2.7	5.5	V	
Ambient Temperature	T_{A}	- 40	25	85	°C	

 $^{^{1)}}$ A Ceramic Bypass Capacitor of 100 nF at $V_{
m S}$ to GND is highly recommended.

AC/DC Characteristics

Parameter	Symbol	Limit Values			Unit	Notes
		Min.	typ.	Max.		
Averaged Supply Current	I_{SAVG}	1	4	20	μA	
Averaged Supply Current	I_{SOPAVG}	0.5	1.1	2.5	mA	
during Operating Time				_		
Transient Peak Supply Current during Operating Time	I_{SOPT}	_	_	2.5	mA	<i>t</i> < 100 ns
Supply Current during Standby Time	I_{SSTB}	1	3.5	20	μΑ	
Output Saturation Voltage	V_{QSAT}	_	0.13	0.4	V	$I_{Q} = 1 \text{ mA}$
Output Leakage Current	I_{QLEAK}	_	0.01	1	μΑ	
Output Rise Time	t _r	_	0.5	1	μs	R_{L} = 2.7 k Ω ; C_{L} = 10 pF
Output Fall Time	t_{f}	_	0.1	1	μs	R_{L} = 2.7 k Ω ; C_{L} = 10 pF
Operating Time	$t_{\sf op}$	15	50	93 1) 2)	μs	
Standby Time	t_{stb}	_	130	240 ³⁾	ms	
Duty Cycle	t_{op} / t_{stb}	_	0.039	_	%	
Start-up Time of IC	t_{stu}	_	6	12	μs	4)

 $^{^{1)}}$ for Vs=3.5V the max. Operating Time $t_{\rm op\ max}$ = 85µs

 $^{^{2)}}$ includes the Start-up Time $t_{\rm stu}$

 $^{^{3)}}$ for V_S=3.5V the max. Standby Time $t_{\rm stb\ max}$ = 220ms

initial power on time. V_S must be applied in this time (typ. 6µs to max. 12µs) to get already a valid output state after the first operating phase (typ. 56µs). For rise times of $V_S > 12µs$, the output state is valid after the second operating phase (includes one standby phase), e.g. happens only when the battery in flip phones is changed.



Magnetic Characteristics

Parameter	Symbol	Limit Values			Unit	Notes
		min.	typ.	max.		
Operate Points	B _{OPS}	2	3.5	5	mT	1)
(Output on)	B _{OPN}	- 5	- 3.5	- 2	mT	
Release Points	B _{RPS}	1,2	2.7	4.2	mT	1)
(Output off)	B_RPN	- 4.2	- 2.6	- 1,2	mT	
Hysteresis	B _{HYS}	0.2	0.8	1,6	mT	

¹⁾ Positive magnetic fields are related to the approach of a magnetic south pole to the branded side of package

Note: The listed AC/DC and magnetic characteristics are ensured over the operating range of the integrated circuit. Typical characteristics specify mean values expected over the production spread. If not other specified, typical characteristics apply at T_j = 25 °C and V_S = 2.7 V



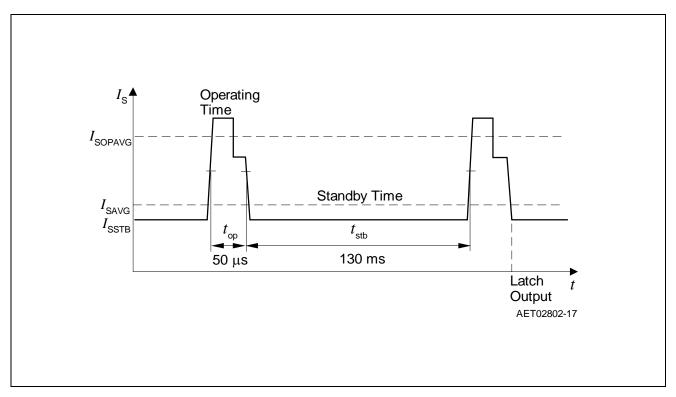


Figure 3 Timing Diagram

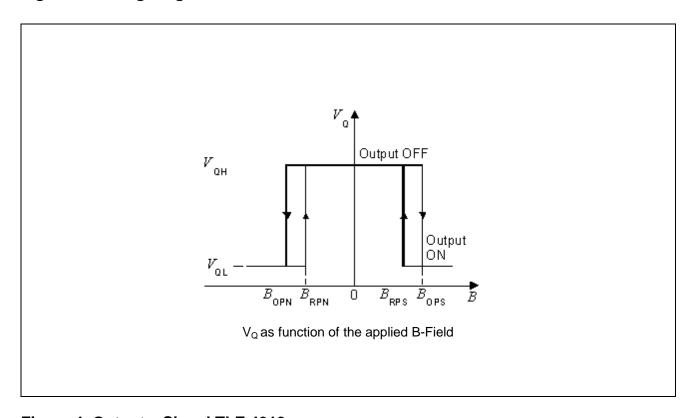
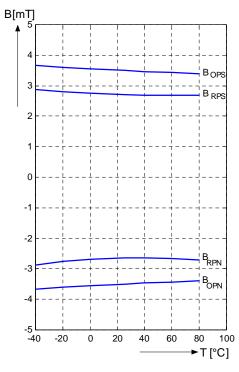


Figure 4 Output – Signal TLE 4913

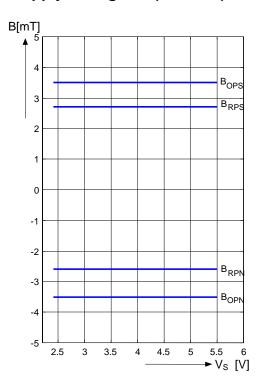


All curves reflect typical values at the given parameters for T_A in °C and V_S in V.

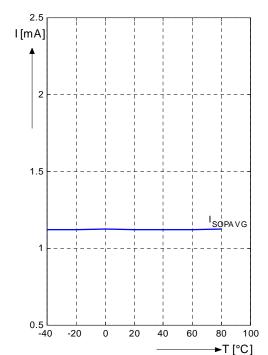
Magnetic Switching Points versus Temperature ($V_S=2.7V$)



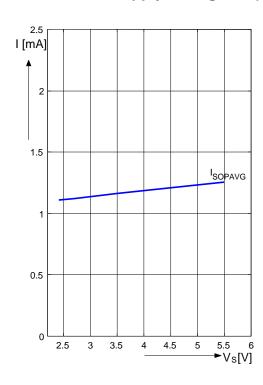
Magnetic Switching Points versus Supply Voltage V_S ($T_A=20$ °C)



Supply current I_{SOPAVG} during Operating Time versus Temperature ($V_S=2.7V$)



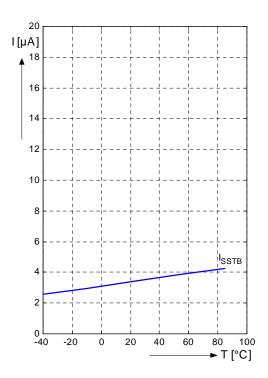
Supply current I_{SOPAVG} during Operating Time versus Supply Voltage V_S ($T_A=20^{\circ}C$)



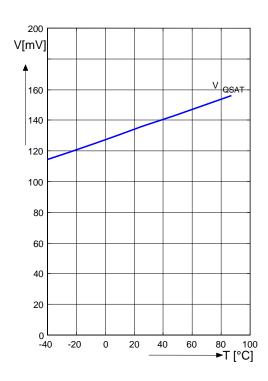
Data Sheet 8 V 2.3, 2019-05-14



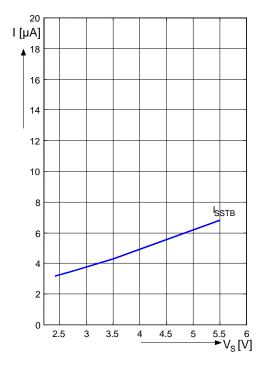
Supply current I_{SSTB} during Standby Time versus Temperature ($V_{S}=2.7V$)



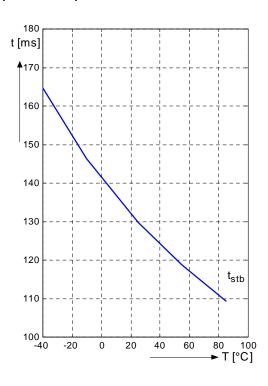
Output Saturation voltage V_{QSAT} versus Temperature ($I_{Q}=1mA$)



Supply current I_{SSTB} during Standby Time versus Supply Voltage V_S ($T_A=20^{\circ}C$)



Standby Time t_{stb} versus Temperature $(V_S = 2.7V)$





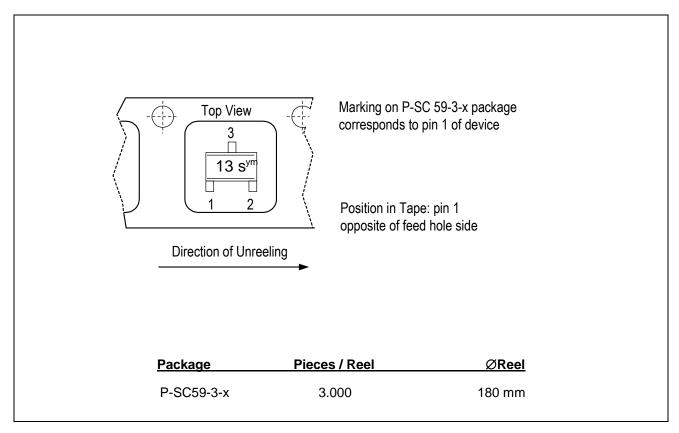


Figure 5 Marking and Tape Loading Orientation

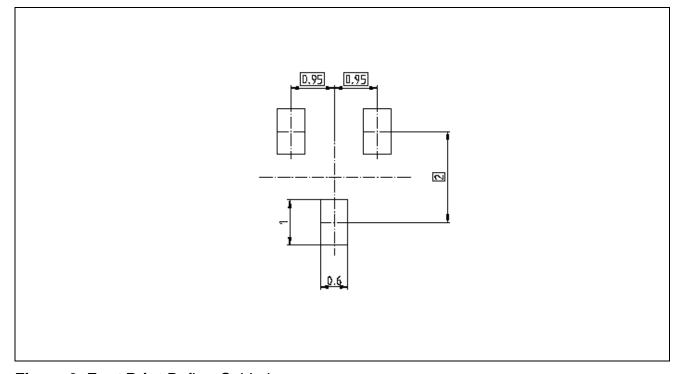
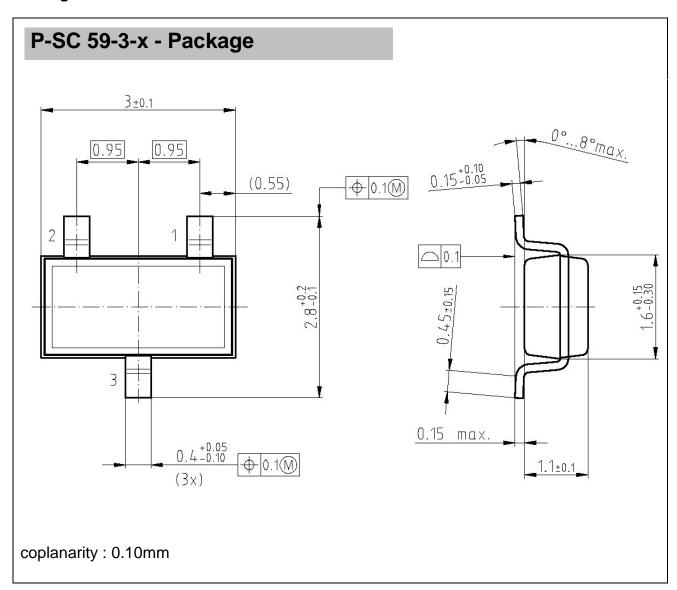


Figure 6 Foot Print Reflow Soldering



Package Dimensions



Sorts of Packing

Package outlines for tubes, trays etc. are contained in our Data Book "Package Information".

SMD = Surface Mounted Device



TLE4913		
Revision His	story: 2019-05-14	V 2.3
Previous Ver	rsion: 2003-07-16 and 2004-03-09	
Page	Subjects (major changes since last revision)	
4	ESD Level adapted to ±4 kV	
1	Change of Ordering Code from Q62705K 619 into SP000013490	

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